

Specification for Approval

Date: 2016/6/29

Certificate of Green Partner
Customer : 深圳臺慶
TAI-TECH P/N: GHB0603HF-Series
CUSTOMER P/N: _____

DESCRIPTION: _____

QUANTITY: _____ pcs

REMARK:		
Customer Approval Feedback		

西北臺慶科技股份有限公司
TAI-TECH Advanced Electronics Co., Ltd

- 西北臺慶科技股份有限公司
 TAI-TECH Advanced Electronics Co., Ltd
Headquarter:
 NO.1 YOU 4TH ROAD, YOUTH INDUSTRIAL DISTRICT, YANG-MEI,
 TAO-YUAN HSIEN, TAIWAN, R.O.C.
 TEL: +886-3-4641148 FAX: +886-3-4643565
 http://www.tai-tech.com.tw
 E-mail: sales@tai-tech.com.tw

- 東莞臺慶精密電子有限公司
 DONGGUAN TAI-TECH ADVANCED ELECTRONICS CO., LTD
 JITIGANG MANAGEMENT DISTRICT, HUANGJIANG, DONGGUAN,
 GUANGDONG, CHINA
 TEL: +86-769-3365488 FAX: +86-769-3366896
 E-mail: twnwe@pub.dgnet.gd.cn

Office:
 金亨國際有限公司
 KAMHENG INTERNATIONAL LIMITED
 TEL: +86-852-25772033 FAX: +86-852-28817778

- 臺慶精密電子(昆山)有限公司
 TAI-TECH ADVANCED ELECTRONICS(KUNSHAN) CO., LTD
 SHINWHA ROAD, KUNJIA HI-TECH INDUSTRIAL PARK, KUN-SHAN,
 JIANG-SU, CHINA
 TEL: +86-512-57619396 FAX: +86-512-57619688
 E-mail: hui@tai-tech.com.tw

Office:
 北欣國際有限公司
 NORTH STAR INTERNATIONAL LIMITED
 TEL: +86-512-57619396 FAX: +86-512-57619688

Sales Dep.

APPROVED	CHECKED
管哲頌 Eric Guan	曾詩涵 Angela Tseng

R&D Center

APPROVED	CHECKED	DRAWN
楊祥忠 Mike Yang	詹偉特 Jack Chan	張嘉玲 Alin Chang

Ferrite Chip Bead for GHz Range Noise Suppression (Lead Free)

GHB0603HF-Series

ECN HISTORY LIST

REV	DATE	DESCRIPTION	APPROVED	CHECKED	DRAWN
1.0	13/10/29	初版發行	楊祥忠	羅培君	張嘉玲
2.0	14/01/24	變更電鍍錫層厚度 3.0um min. =>3.5um min.	楊祥忠	羅培君	張嘉玲
3.0	14/08/01	變更 Reflow 圖示	楊祥忠	羅培君	張嘉玲
4.0	16/01/26	增訂可靠度 Thermal shock: (Bead) Step3 : 125±2°C 30±5min	楊祥忠	詹偉特	張嘉玲
備 註					

Ferrite Chip Bead for GHz Range Noise Suppression (Lead Free)

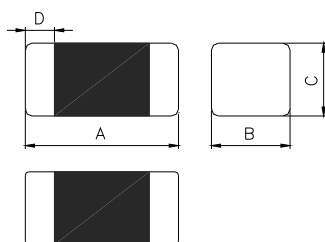
GHB0603HF-Series

1.Features

- 1.Monolithic inorganic material construction.
- 2.Closed magnetic circuit avoids crosstalk.
- 3.S.M.T. type.
- 4.Suitable for reflow soldering.
- 5.The GHB1005 series is intended for standard signal lines as this series provides significant impedance across a broad frequency range.
- 6.The magnetic shielded structure minimizes crosstalk.
- 7.100% Lead(Pb) & Halogen-Free and RoHS compliant.



Certificate
of
GreenPartner

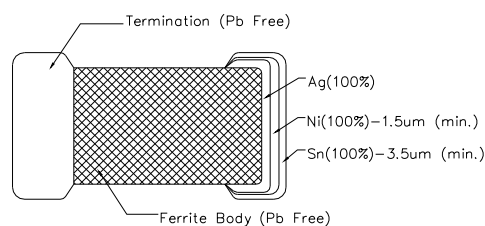
2.Dimensions

Chip Size	
A	0.60±0.03
B	0.30±0.03
C	0.30±0.03
D	0.15±0.05

Unit : mm

3.Part Numbering

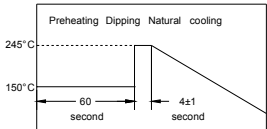
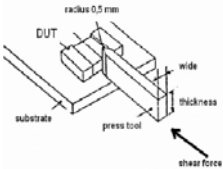
- A: Series
 B: Dimension L x W
 C: Material **Lead Free Material**
 D: Impedance **102=1000Ω**
 E: Packaging T=Taping and Reel, B=Bulk(Bags)
 F: Rated Current

**4.Specification**

Tai-Tech Part Number	Impedance (Ω)	Test Frequency (Hz)	DC Resistance (Ω) max.	Rated Current (mA) max.
GHB0603HF-601T01	600±25%	60mV/100M	1.5	160
GHB0603HF-102T01	1000±25%	60mV/100M	2.5	130
GHB0603HF-152T01	1500±25%	60mV/100M	3.2	115

- Rated current: based on temperature rise test
- In compliance with EIA 595

5. Reliability and Test Condition

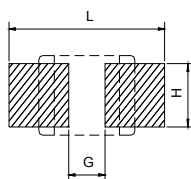
Item	Performance										Test Condition				
	FCB	FCM	HCB	GHB	FCA	FCI	FHI	FCH	HCI	--					
Series No.															
Operating Temperature	-40~+125°C (Including self-temperature rise)					-40~+105°C (Including self-temperature rise)					--				
Transportation Storage Temperature	-40~+125°C (on board)					-40~+105°C (on board)					For long storage conditions, please see the Application Notice				
Impedance (Z)	Refer to standard electrical characteristics list										Agilent4291				
Inductance (Ls)											Agilent E4991				
Q Factor											Agilent4287				
DC Resistance											Agilent16192				
Rated Current											Agilent 4338				
Temperature Rise Test	Rated Current < 1A ΔT 20°C Max										1. Applied the allowed DC current.				
	Rated Current ≥ 1A ΔT 40°C Max										2. Temperature measured by digital surface thermometer.				
Resistance to Soldering Heat	Appearance : No damage. Impedance : within±15% of initial value Inductance : within±10% of initial value Q : Shall not exceed the specification value. RDC : within ±15% of initial value and shall not exceed the specification value										Number of heat cycles: 1				
											<table border="1"> <thead> <tr> <th>Temperature (°C)</th> <th>Time (s)</th> <th>Temperature ramp/immersion and emersion rate</th> </tr> </thead> <tbody> <tr> <td>260 ±5 (solder temp)</td> <td>10 ±1</td> <td>25mm/s ±6 mm/s</td> </tr> </tbody> </table> Depth: completely cover the termination	Temperature (°C)	Time (s)	Temperature ramp/immersion and emersion rate	260 ±5 (solder temp)
Temperature (°C)	Time (s)	Temperature ramp/immersion and emersion rate													
260 ±5 (solder temp)	10 ±1	25mm/s ±6 mm/s													
Solderability	More than 95% of the terminal electrode should be covered with solder. 										Preheat: 150°C, 60sec. Solder: Sn96.5%-Ag3%-Cu0.5% Solder temperature: 245±5°C Flux for lead free: Rosin. 9.5% Depth: completely cover the termination. Dip time: 4±1sec.				
Terminal strength	Appearance : No damage. Impedance : within±15% of initial value Inductance : within±10% of initial value Q : Shall not exceed the specification value. RDC : within ±15% of initial value and shall not exceed the specification value 										Preconditioning: Run through IR reflow for 2 times.(IPC/JEDEC J-STD-020D Classification Reflow Profiles) Component mounted on a PCB apply a force (>0805:1kg <=0805:0.5kg)to the side of a device being tested. This force shall be applied for 60 +1 seconds. Also the force shall be applied gradually as not to shock the component being tested.				
Bending	Appearance : No damage. Impedance : within±10% of initial value Inductance : within±10% of initial value Q : Shall not exceed the specification value. RDC : within ±15% of initial value and shall not exceed the specification value										Shall be mounted on a FR4 substrate of the following dimensions:>=0805:40x100x1.2mm <0805:40x100x0.8mm Bending depth:>=0805:1.2mm <0805:0.8mm Duration of 10 sec for a min.				
Vibration Test	Appearance : No damage. Impedance : within±15% of initial value Inductance : within±10% of initial value Q : Shall not exceed the specification value. RDC : within ±15% of initial value and shall not exceed the specification value										Preconditioning: Run through IR reflow for 2 times.(IPC/JEDEC J-STD-020D Classification Reflow Profiles) Oscillation Frequency: 10 ~ 2K ~ 10Hz for 20 minutes Equipment : Vibration checker Total Amplitude:1.52mm±10% Testing Time : 12 hours(20 minutes, 12 cycles each of 3 orientations)				
Shock	Appearance : No damage. Impedance : within±10% of initial value Inductance : within±10% of initial value Q : Shall not exceed the specification value. RDC : within ±15% of initial value and shall not exceed the specification value										Test condition:				
											<table border="1"> <thead> <tr> <th>Type</th> <th>Peak Value (g's)</th> <th>Normal duration (D) (ms)</th> <th>Wave form</th> <th>Velocity change (V)/ft/sec</th> </tr> </thead> <tbody> <tr> <td>SMD</td> <td>50</td> <td>11</td> <td>Half-sine</td> <td>11.3</td> </tr> <tr> <td>Lead</td> <td>50</td> <td>11</td> <td>Half-sine</td> <td>11.3</td> </tr> </tbody> </table>	Type	Peak Value (g's)	Normal duration (D) (ms)	Wave form
Type	Peak Value (g's)	Normal duration (D) (ms)	Wave form	Velocity change (V)/ft/sec											
SMD	50	11	Half-sine	11.3											
Lead	50	11	Half-sine	11.3											

Item	Performance	Test Condition
Life test	Appearance: no damage. Impedance: within±15%of initial value. Inductance: within±10%of initial value. Q : Shall not exceed the specification value. RDC : within ±15% of initial value and shall not exceed the specification value	Preconditioning: Run through IR reflow for 2 times.(IPC/JEDEC J-STD-020D Classification Reflow Profiles) Temperature: 125±2℃(Bead), 105±2℃(Inductor) Applied current: rated current. Duration: 1000±12hrs. Measured at room temperature after placing for 24±2 hrs.
Load Humidity	Appearance: no damage. Impedance: within±15%of initial value. Inductance: within±10%of initial value. Q : Shall not exceed the specification value. RDC : within ±15% of initial value and shall not exceed the specification value	Preconditioning: Run through IR reflow for 2 times.(IPC/JEDEC J-STD-020D Classification Reflow Profiles) Humidity: 85±2%R.H. Temperature: 85±2℃. Duration: 1000hrs Min. with 100% rated current. Measured at room temperature after placing for 24±2 hrs.
Thermal shock	Appearance: no damage. Impedance: within±15%of initial value. Inductance: within±10%of initial value. Q : Shall not exceed the specification value. RDC : within ±15% of initial value and shall not exceed the specification value	Preconditioning: Run through IR reflow for 2 times.(IPC/JEDEC J-STD-020D Classification Reflow Profiles) Condition for 1 cycle Step1: -40±2℃ 30±5 min. Step2: 25±2℃ ≤0.5min Step3: +125±2℃ 30±5min. (Bead) Step3: +105±2℃ 30±5min. (Inductor) Number of cycles: 500 Measured at room temperature after placing for 24±2 hrs.
Insulation Resistance	IR>1GΩ	Chip Inductor Only Test Voltage:100±10%V for 30Sec.

6.Soldering and Mounting

6-1. Recommended PC Board Pattern

Chip Size						Land Patterns For Reflow Soldering		
Series	Type	A(mm)	B(mm)	C(mm)	D(mm)	L(mm)	G(mm)	H(mm)
GHB	0603	0.6±0.03	0.30±0.03	0.30±0.03	0.15±0.05	0.80	0.30	0.30



PC board should be designed so that products can prevent damage from mechanical stress when warping the board.

6-2. Soldering

Mildly activated rosin fluxes are preferred. The terminations are suitable for re-flow soldering systems. If hand soldering cannot be avoided, the preferred technique is the utilization of hot air soldering tools.

Note.

If wave soldering is used ,there will be some risk.

Re-flow soldering temperatures below 240 degrees, there will be non-wetting risk

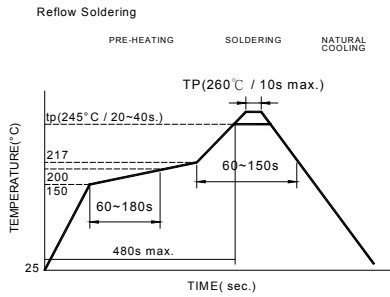
6-2.1 Lead Free Solder re-flow:

Recommended temperature profiles for lead free re-flow soldering in Figure 1. (Referred to J-STD-020C)

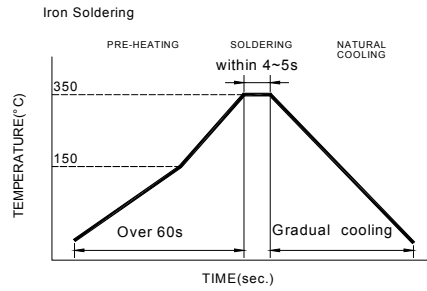
6-2.2 Soldering Iron:

Products attachment with a soldering iron is discouraged due to the inherent process control limitations. If a soldering iron must be employed the following precautions are recommended. for Iron Soldering in Figure 2.

- Preheat circuit and products to 150°C
- Never contact the ceramic with the iron tip
- Use a 20 watt soldering iron with tip diameter of 1.0mm
- 350°C tip temperature (max)
- 1.0mm tip diameter (max)
- Limit soldering time to 4~5sec.



Reflow times: 3 times max
Fig.1

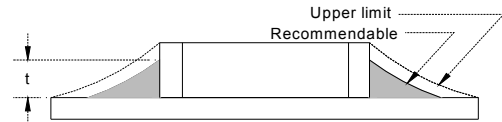


Iron Soldering times : 1 times max
Fig.2

6-2.3 Solder Volume:

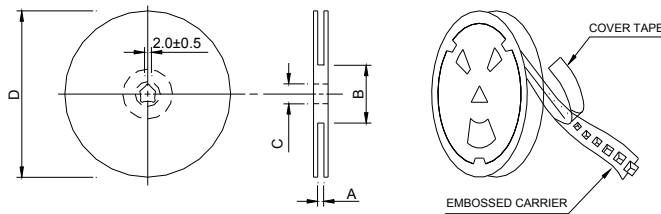
Accordingly increasing the solder volume, the mechanical stress to product is also increased. Exceeding solder volume may cause the failure of mechanical or electrical performance. Solder shall be used not to be exceed as shown in right side:

Minimum fillet height = soldering thickness + 25% product height



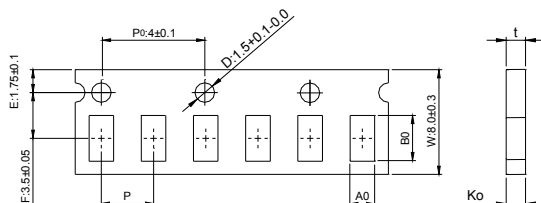
7.Packaging Information

7-1. Reel Dimension



Type	A(mm)	B(mm)	C(mm)	D(mm)
7"x8mm	10±1.5	50 min	13±0.2	178±2

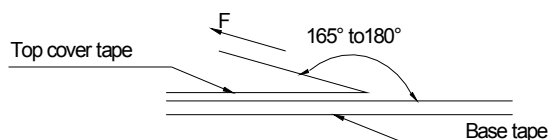
7-2. Tape Dimension / 8mm



Size	Bo(mm)	Ao(mm)	Ko(mm)	P(mm)	t(mm)
060303	0.70±0.06	0.40±0.06	0.45max	2.0±0.05	0.50max

7-3. Packaging Quantity

Chip Size	060303
Chip / Reel	15000
Inner box	75000
Middle box	375000
Carton	750000

7-4. Tearing Off Force

The force for tearing off cover tape is 15 to 60 grams in the arrow direction under the following conditions.

Room Temp. (°C)	Room Humidity (%)	Room atm (hPa)	Tearing Speed mm/min
5~35	45~85	860~1060	300

Application Notice

• Storage Conditions

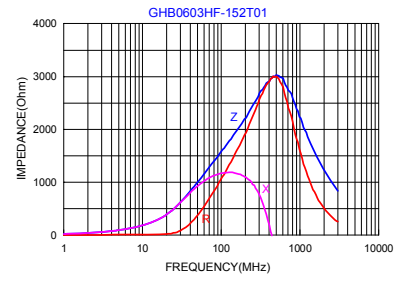
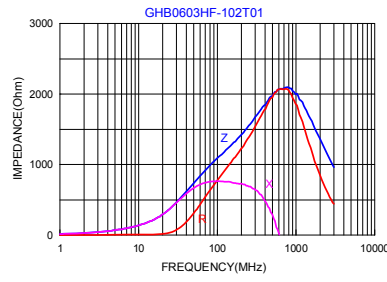
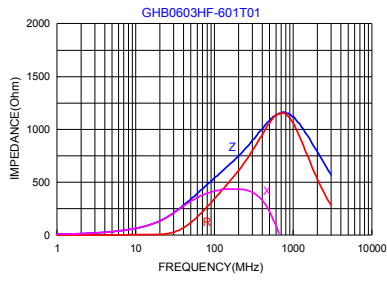
To maintain the solder ability of terminal electrodes:

1. TAI-TECH products meet IPC/JEDEC J-STD-020D standard-MSL, level 1.
2. Temperature and humidity conditions: Less than 40°C and 60% RH.
3. Recommended products should be used within 12 months from the time of delivery.
4. The packaging material should be kept where no chlorine or sulfur exists in the air.

• Transportation

1. Products should be handled with care to avoid damage or contamination from perspiration and skin oils.
2. The use of tweezers or vacuum pick up is strongly recommended for individual components.
3. Bulk handling should ensure that abrasion and mechanical shock are minimized.

Impedance Frequency Characteristics(Typical)





測試報告 Test Report

號碼(No.) : CE/2015/C2559 日期(Date) : 2015/12/21


頁數(Page): 1 of 16

西北臺慶科技股份有限公司 / TAI-TECH ADVANCED ELECTRONICS CO., LTD.
(臺慶精密電子(昆山)有限公司 / TAI-TECH ADVANCED ELECTRONICS (KUN-SHAN) CO. LTD.)
(耀鑽科技股份有限公司 / YOSONIC TECHNOLOGY CO., LTD.)
(慶邦電子元器件(泗洪)有限公司 / TAIPAQ ELECTRONICS (SI-HONG) CO., LTD.)
桃園市楊梅區幼獅工業區幼四路1號 (NO. 1, YOU 4TH ROAD, YOUTH INDUSTRIAL DISTRICT, YANG-MEI, TAO-YUAN CITY, TAIWAN, R. O. C.)
(江蘇省昆山市蓬朗區嘉高科技工業區郭澤路 / GUO-ZE ROAD, KUNJIA HI-TECH INDUSTRIAL PARK, KUN-SHAN, JIANG-SU, CHINA)
(桃園市中壢區中壢工業區長春六路15號 / NO. 15, CHANGCHUN 6TH RD., JHONGLI DISTRICT, TAOYUAN CITY 320, TAIWAN)
(江蘇省宿遷市泗洪縣經濟開發區金沙南路-高新技術產業園 / HIGH-TECH INDUSTRIAL DISTRICT, JINSHAJIANG ROAD, SIHONG COUNTY ECONOMIC, SUQIAN CITY, JIANGSU)

以下測試樣品係由申請廠商所提供及確認 (The following sample(s) was/were submitted and identified by/on behalf of the applicant as):

樣品名稱(Sample Description)	:	FERRITE CHIP BEAD INDUCTOR ARRAY MCF MCM YMV SERIES
樣品型號(Style/Item No.)	:	FERRITE CHIP BEAD INDUCTOR ARRAY MCF MCM YMV SERIES
收件日期(Sample Receiving Date)	:	2015/12/14
測試期間(Testing Period)	:	2015/12/14 TO 2015/12/21

=====
測試結果(Test Results) : 請見下一頁 (Please refer to next pages).



Troy Chang, Manager - Tech
Signed for and on behalf of
SGS TAIWAN LTD.
Chemical Laboratory - Taipei

This document is issued by the Company subject to its General Conditions of Service printed overleaf, available on request or accessible at <http://www.sgs.com.tw/terms-and-conditions.aspx> and, for electronic format documents, subject to Terms and Conditions for Electronic Documents at <http://www.sgs.com.tw/terms-and-conditions-for-electronic-documents.aspx>. Attention is drawn to the limitation of liability, indemnification and jurisdiction issues defined therein. Any holder of this document is advised that information contained hereon reflects the Company's findings at the time of its intervention only and within the limits of client's instruction, if any. The Company's sole responsibility is to its Client and this document does not exonerate parties to a transaction from exercising all their rights and obligations under the transaction documents. This document cannot be reproduced, except in full, without prior written approval of the Company. Any unauthorized alteration, forgery or falsification of the content or appearance of this document is unlawful and offenders may be prosecuted to the fullest extent of the law. Unless otherwise stated the results shown in this test report refer only to the sample(s) tested.



測試報告 Test Report

號碼(No.) : CE/2015/C2559 日期(Date) : 2015/12/21

頁數(Page): 2 of 16

西北臺慶科技股份有限公司 / TAI-TECH ADVANCED ELECTRONICS CO., LTD.

(臺慶精密電子(昆山)有限公司 / TAI-TECH ADVANCED ELECTRONICS (KUN-SHAN) CO. LTD.)

(耀鑽科技股份有限公司 / YOSONIC TECHNOLOGY CO., LTD.)

(慶邦電子元件(泗洪)有限公司 / TAIPAQ ELECTRONICS (SI-HONG) CO., LTD.)

桃園市楊梅區幼獅工業區幼四路1號 (NO. 1, YOU 4TH ROAD, YOUTH INDUSTRIAL DISTRICT, YANG-MEI, TAO-YUAN CITY, TAIWAN, R. O. C.)

(江蘇省昆山市蓬朗鎮嘉高科技工業區郭澤路 / GUO-ZE ROAD, KUNJIA HI-TECH INDUSTRIAL PARK, KUN-SHAN, JIANG-SU, CHINA)

(桃園市中壢區中壢工業區長春六路15號 / NO. 15, CHANGCHUN 6TH RD., JHONGLI DISTRICT, TAOYUAN CITY 320, TAIWAN)

(江蘇省宿遷市泗洪縣經濟開發區金沙南路-高新技術產業園 / HIGH-TECH INDUSTRIAL DISTRICT, JINSHAJIANG ROAD, SIHONG COUNTY ECONOMIC, SUQIAN CITY, JIANGSU)

測試結果(Test Results)

測試部位(PART NAME)No. 1 : 整體混測 (MIXED ALL PARTS)

測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測 極限值 (MDL)	結果 (Result)
				No. 1
鎘 / Cadmium (Cd)	mg/kg	參考IEC 62321-5: 2013方法, 以感應耦合電漿原子發射光譜儀檢測. / With reference to IEC 62321-5: 2013 and performed by ICP-AES.	2	n. d.
鉛 / Lead (Pb)	mg/kg	參考IEC 62321-5: 2013方法, 以感應耦合電漿原子發射光譜儀檢測. / With reference to IEC 62321-5: 2013 and performed by ICP-AES.	2	25.7
汞 / Mercury (Hg)	mg/kg	參考IEC 62321-4: 2013方法, 以感應耦合電漿原子發射光譜儀檢測. / With reference to IEC 62321-4: 2013 and performed by ICP-AES.	2	n. d.
六價鉻 / Hexavalent Chromium Cr(VI)	mg/kg	參考IEC 62321: 2008方法, 以UV-VIS檢測. / With reference to IEC 62321: 2008 and performed by UV-VIS.	2	n. d.
銻 / Antimony (Sb)	mg/kg	參考US EPA 3052方法, 以感應耦合電漿原子發射光譜儀檢測. / With reference to US EPA Method 3052. Analysis was performed by ICP-AES.	2	n. d.
鈹 / Beryllium (Be)	mg/kg	參考US EPA 3052方法, 以感應耦合電漿原子發射光譜儀檢測. / With reference to US EPA Method 3052. Analysis was performed by ICP-AES.	2	n. d.

This document is issued by the Company subject to its General Conditions of Service printed overleaf, available on request or accessible at <http://www.sgs.com.tw/Terms-and-Conditions.aspx> and, for electronic format documents, subject to Terms and Conditions for Electronic Documents at <http://www.sgs.com.tw/Service/Conditions/Terms-and-Conditions.aspx>. Attention is drawn to the limitation of liability, indemnification and jurisdiction issues defined therein. Any holder of this document is advised that information contained herein reflects the Company's findings at the time of its intervention only and within the limits of client's instruction, if any. The Company's sole responsibility is to its Client and this document does not exonerate parties to a transaction from exercising all their rights and obligations under the transaction documents. This document cannot be reproduced, except in full, without prior written approval of the Company. Any unauthorized alteration, forgery or falsification of the content or appearance of this document is unlawful and offenders may be prosecuted to the fullest extent of the law. Unless otherwise stated the results shown in this test report refer only to the sample(s) tested.



測試報告

Test Report

號碼(No.) : CE/2015/C2559

日期(Date) : 2015/12/21

頁數(Page): 3 of 16

西北臺慶科技股份有限公司 / TAI-TECH ADVANCED ELECTRONICS CO., LTD.

(臺慶精密電子(昆山)有限公司 / TAI-TECH ADVANCED ELECTRONICS (KUN-SHAN) CO. LTD.)

(耀鑽科技股份有限公司 / YOSONIC TECHNOLOGY CO., LTD.)

(慶邦電子元器件(泗洪)有限公司 / TAIPAQ ELECTRONICS (SI-HONG) CO., LTD.)

桃園市楊梅區幼獅工業區幼四路1號 (NO. 1, YOU 4TH ROAD, YOUTH INDUSTRIAL DISTRICT, YANG-MEI, TAO-YUAN CITY, TAIWAN, R. O. C.)

(江蘇省昆山市蓬朗昆嘉高科技工業區郭澤路 / GUO-ZE ROAD, KUNJIA HI-TECH INDUSTRIAL PARK, KUN-SHAN, JIANG-SU, CHINA)

(桃園市中壢區中壢工業區長春六路15號 / NO. 15, CHANGCHUN 6TH RD., JHONGLI DISTRICT, TAOYUAN CITY 320, TAIWAN)

(江蘇省宿遷市泗洪縣經濟開發區金沙南路-高新技術產業園 / HIGH-TECH INDUSTRIAL DISTRICT, JINSHAJIANG ROAD, SIHONG COUNTY ECONOMIC, SUQIAN CITY, JIANGSU)

測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測 極限值 (MDL)	結果 (Result)
				No. 1
全氟辛烷磺酸 / Perfluorooctane sulfonates (PFOS-Acid, Metal Salt, Amide)	mg/kg	參考US EPA 3550C: 2007方法, 以液相層析/質譜儀檢測. / With reference to US EPA 3550C: 2007. Analysis was performed by LC/MS.	10	n. d.
全氟辛酸 / PFOA (CAS No.: 335-67-1)	mg/kg	參考US EPA 3550C: 2007方法, 以液相層析/質譜儀檢測. / With reference to US EPA 3550C: 2007. Analysis was performed by LC/MS.	10	n. d.
聚氯乙烯 / PVC	**	以紅外光譜分析及焰色法檢測. / Analysis was performed by FTIR and FLAME Test.	-	Negative
鄰苯二甲酸丁苯甲酯 / BBP (Butyl Benzyl phthalate) (CAS No.: 85-68-7)	mg/kg	參考IEC 62321-8 (111/321/CD), 以氣相層析儀/質譜儀檢測之. / With reference to IEC 62321-8 (111/321/CD). Analysis was performed by GC/MS.	50	n. d.
鄰苯二甲酸二丁酯 / DBP (Dibutyl phthalate) (CAS No.: 84-74-2)	mg/kg	參考IEC 62321-8 (111/321/CD), 以氣相層析儀/質譜儀檢測之. / With reference to IEC 62321-8 (111/321/CD). Analysis was performed by GC/MS.	50	n. d.

This document is issued by the Company subject to its General Conditions of Service printed overleaf, available on request or accessible at <http://www.sgs.com.tw/terms-and-conditions.aspx> and, for electronic format documents, subject to Terms and Conditions for Electronic Documents at <http://www.sgs.com.tw/terms-and-conditions-for-electronic-format-document.aspx>. Attention is drawn to the limitation of liability, indemnification and jurisdiction issues defined therein. Any holder of this document is advised that information contained hereon reflects the Company's findings at the time of its intervention only and within the limits of client's instruction, if any. The Company's sole responsibility is to its Client and this document does not exonerate parties to a transaction from exercising all their rights and obligations under the transaction documents. This document cannot be reproduced, except in full, without prior written approval of the Company. Any unauthorized alteration, forgery or falsification of the content or appearance of this document is unlawful and offenders may be prosecuted to the fullest extent of the law. Unless otherwise stated the results shown in this test report refer only to the sample(s) tested.



測試報告 Test Report

號碼(No.) : CE/2015/C2559 日期(Date) : 2015/12/21

頁數(Page): 4 of 16

西北臺慶科技股份有限公司 / TAI-TECH ADVANCED ELECTRONICS CO., LTD.

(臺慶精密電子(昆山)有限公司 / TAI-TECH ADVANCED ELECTRONICS (KUN-SHAN) CO. LTD.)

(耀鑽科技股份有限公司 / YOSONIC TECHNOLOGY CO., LTD.)

(慶邦電子元器件(泗洪)有限公司 / TAIPAQ ELECTRONICS (SI-HONG) CO., LTD.)

桃園市楊梅區幼獅工業區幼四路1號 (NO. 1, YOU 4TH ROAD, YOUTH INDUSTRIAL DISTRICT, YANG-MEI, TAO-YUAN CITY, TAIWAN, R. O. C.)

(江蘇省昆山市蓬朗昆嘉高科技工業區郭澤路 / GUO-ZE ROAD, KUNJIA HI-TECH INDUSTRIAL PARK, KUN-SHAN, JIANG-SU, CHINA)

(桃園市中壢區中壢工業區長春六路15號 / NO. 15, CHANGCHUN 6TH RD., JHONGLI DISTRICT, TAOYUAN CITY 320, TAIWAN)

(江蘇省宿遷市泗洪縣經濟開發區金沙南路-高新技術產業園 / HIGH-TECH INDUSTRIAL DISTRICT, JINSHAJIANG ROAD, SIHONG COUNTY ECONOMIC, SUQIAN CITY, JIANGSU)

測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測 極限值 (MDL)	結果 (Result)
				No. 1
鄰苯二甲酸二(2-乙基己基)酯 / DEHP (Di-(2-ethylhexyl) phthalate) (CAS No.: 117-81-7)	mg/kg	參考IEC 62321-8 (111/321/CD), 以氣 相層析儀/質譜儀檢測之。 / With reference to IEC 62321-8 (111/321/CD). Analysis was performed by GC/MS.	50	n. d.
鄰苯二甲酸二異丁酯 / DIBP (Di- isobutyl phthalate) (CAS No.: 84-69- 5)	mg/kg	參考IEC 62321-8 (111/321/CD), 以氣 相層析儀/質譜儀檢測之。 / With reference to IEC 62321-8 (111/321/CD). Analysis was performed by GC/MS.	50	n. d.
鄰苯二甲酸二異癸酯 / DIDP (Di- isodecyl phthalate) (CAS No.: 26761- 40-0; 68515-49-1)	mg/kg	參考IEC 62321-8 (111/321/CD), 以氣 相層析儀/質譜儀檢測之。 / With reference to IEC 62321-8 (111/321/CD). Analysis was performed by GC/MS.	50	n. d.
鄰苯二甲酸二異壬酯 / DINP (Di- isononyl phthalate) (CAS No.: 28553- 12-0; 68515-48-0)	mg/kg	參考IEC 62321-8 (111/321/CD), 以氣 相層析儀/質譜儀檢測之。 / With reference to IEC 62321-8 (111/321/CD). Analysis was performed by GC/MS.	50	n. d.
鄰苯二甲酸二正辛酯 / DNOP (Di-n- octyl phthalate) (CAS No.: 117-84-0)	mg/kg	參考IEC 62321-8 (111/321/CD), 以氣 相層析儀/質譜儀檢測之。 / With reference to IEC 62321-8 (111/321/CD). Analysis was performed by GC/MS.	50	n. d.

This document is issued by the Company subject to its General Conditions of Service printed overleaf, available on request or accessible at <http://www.sgs.com/en/terms-and-conditions.aspx> and, for electronic format documents, subject to Terms and Conditions for Electronic Documents at <http://www.sgs.com/en/terms-and-conditions-for-electronic-documents.aspx>. Attention is drawn to the limitation of liability, indemnification and jurisdiction issues defined therein. Any holder of this document is advised that information contained herein reflects the Company's findings at the time of its intervention only and within the limits of client's instruction, if any. The Company's sole responsibility is to its Client and this document does not exonerate parties to a transaction from exercising all their rights and obligations under the transaction documents. This document cannot be reproduced, except in full, without prior written approval of the Company. Any unauthorized alteration, forgery or falsification of the content or appearance of this document is unlawful and offenders may be prosecuted to the fullest extent of the law. Unless otherwise stated the results shown in this test report refer only to the sample(s) tested.



測試報告 Test Report

號碼(No.) : CE/2015/C2559 日期(Date) : 2015/12/21

頁數(Page): 5 of 16

西北臺慶科技股份有限公司 / TAI-TECH ADVANCED ELECTRONICS CO., LTD.

(臺慶精密電子(昆山)有限公司 / TAI-TECH ADVANCED ELECTRONICS (KUN-SHAN) CO. LTD.)

(耀鑽科技股份有限公司 / YOSONIC TECHNOLOGY CO., LTD.)

(慶邦電子元器件(泗洪)有限公司 / TAIPAQ ELECTRONICS (SI-HONG) CO., LTD.)

桃園市楊梅區幼獅工業區幼四路1號 (NO. 1, YOU 4TH ROAD, YOUTH INDUSTRIAL DISTRICT, YANG-MEI, TAO-YUAN CITY, TAIWAN, R. O. C.)

(江蘇省昆山市蓬朗昆嘉高科技工業區郭澤路 / GUO-ZE ROAD, KUNJIA HI-TECH INDUSTRIAL PARK, KUN-SHAN, JIANG-SU, CHINA)

(桃園市中壢區中壢工業區長春六路15號 / NO. 15, CHANGCHUN 6TH RD., JHONGLI DISTRICT, TAOYUAN CITY 320, TAIWAN)

(江蘇省宿遷市泗洪縣經濟開發區金沙南路-高新技術產業園 / HIGH-TECH INDUSTRIAL DISTRICT, JINSHAJIANG ROAD, SIHONG COUNTY ECONOMIC, SUQIAN CITY, JIANGSU)

測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測 極限值 (MDL)	結果 (Result)
				No. 1
鄰苯二甲酸二正己酯 / DNHP (Di-n-hexyl phthalate) (CAS No.: 84-75-3)	mg/kg	參考IEC 62321-8 (111/321/CD), 以氣相層析儀/質譜儀檢測之。 / With reference to IEC 62321-8 (111/321/CD). Analysis was performed by GC/MS.	50	n. d.
六溴環十二烷及所有主要被辨別出的異構物 / Hexabromocyclododecane (HBCDD) and all major diastereoisomers identified (α -HBCDD, β -HBCDD, γ -HBCDD) (CAS No.: 25637-99-4 and 3194-55-6 (134237-51-7, 134237-50-6, 134237-52-8))	mg/kg	參考IEC 62321: 2008方法, 以氣相層析/質譜儀檢測。 / With reference to IEC 62321: 2008 method. Analysis was performed by GC/MS.	5	n. d.
鹵素 / Halogen				
鹵素 (氟) / Halogen-Fluorine (F) (CAS No.: 14762-94-8)	mg/kg	參考BS EN 14582:2007, 以離子層析儀分析。 / With reference to BS EN 14582:2007. Analysis was performed by IC.	50	n. d.
鹵素 (氯) / Halogen-Chlorine (Cl) (CAS No.: 22537-15-1)	mg/kg		50	n. d.
鹵素 (溴) / Halogen-Bromine (Br) (CAS No.: 10097-32-2)	mg/kg		50	n. d.
鹵素 (碘) / Halogen-Iodine (I) (CAS No.: 14362-44-8)	mg/kg		50	n. d.

This document is issued by the Company subject to its General Conditions of Service printed overleaf, available on request or accessible at <http://www.sgs.com.tw/terms-and-conditions.aspx> and, for electronic format documents, subject to Terms and Conditions for Electronic Documents at <http://www.sgs.com.tw/terms-and-conditions/electronic-document.aspx>. Attention is drawn to the limitation of liability, indemnification and jurisdiction issues defined therein. Any holder of this document is advised that information contained herein reflects the Company's findings at the time of its intervention only and within the limits of client's instruction, if any. The Company's sole responsibility is to its Client and this document does not exonerate parties to a transaction from exercising all their rights and obligations under the transaction documents. This document cannot be reproduced, except in full, without prior written approval of the Company. Any unauthorized alteration, forgery or falsification of the content or appearance of this document is unlawful and offenders may be prosecuted to the fullest extent of the law. Unless otherwise stated the results shown in this test report refer only to the sample(s) tested.



測試報告 Test Report

號碼(No.) : CE/2015/C2559

日期(Date) : 2015/12/21

頁數(Page): 6 of 16

西北臺慶科技股份有限公司 / TAI-TECH ADVANCED ELECTRONICS CO., LTD.

(臺慶精密電子(昆山)有限公司 / TAI-TECH ADVANCED ELECTRONICS (KUN-SHAN) CO. LTD.)

(耀鑽科技股份有限公司 / YOSONIC TECHNOLOGY CO., LTD.)

(慶邦電子元器件(泗洪)有限公司 / TAIPAQ ELECTRONICS (SI-HONG) CO., LTD.)

桃園市楊梅區幼獅工業區幼四路1號 (NO. 1, YOU 4TH ROAD, YOUTH INDUSTRIAL DISTRICT, YANG-MEI, TAO-YUAN CITY, TAIWAN, R. O. C.)

(江蘇省昆山市蓬朗昆嘉高科技工業區郭澤路 / GUO-ZE ROAD, KUNJIA HI-TECH INDUSTRIAL PARK, KUN-SHAN, JIANG-SU, CHINA)

(桃園市中壢區中壢工業區長春六路15號 / NO. 15, CHANGCHUN 6TH RD., JHONGLI DISTRICT, TAOYUAN CITY 320, TAIWAN)

(江蘇省宿遷市泗洪縣經濟開發區金沙南路-高新技術產業園 / HIGH-TECH INDUSTRIAL DISTRICT, JINSHAJIANG ROAD, SIHONG COUNTY ECONOMIC, SUQIAN CITY, JIANGSU)

測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測 極限值 (MDL)	結果 (Result)
				No. 1
多溴聯苯總和 / Sum of PBBs	mg/kg	參考 IEC 62321-6: 2015 方法, 以氣相層析/質譜儀檢測。 / With reference to IEC 62321-6: 2015 and performed by GC/MS.	-	n. d.
一溴聯苯 / Monobromobiphenyl	mg/kg		5	n. d.
二溴聯苯 / Dibromobiphenyl	mg/kg		5	n. d.
三溴聯苯 / Tribromobiphenyl	mg/kg		5	n. d.
四溴聯苯 / Tetrabromobiphenyl	mg/kg		5	n. d.
五溴聯苯 / Pentabromobiphenyl	mg/kg		5	n. d.
六溴聯苯 / Hexabromobiphenyl	mg/kg		5	n. d.
七溴聯苯 / Heptabromobiphenyl	mg/kg		5	n. d.
八溴聯苯 / Octabromobiphenyl	mg/kg		5	n. d.
九溴聯苯 / Nonabromobiphenyl	mg/kg		5	n. d.
十溴聯苯 / Decabromobiphenyl	mg/kg		5	n. d.
多溴聯苯醚總和 / Sum of PBDEs	mg/kg		-	n. d.
一溴聯苯醚 / Monobromodiphenyl ether	mg/kg		5	n. d.
二溴聯苯醚 / Dibromodiphenyl ether	mg/kg		5	n. d.
三溴聯苯醚 / Tribromodiphenyl ether	mg/kg		5	n. d.
四溴聯苯醚 / Tetrabromodiphenyl ether	mg/kg		5	n. d.
五溴聯苯醚 / Pentabromodiphenyl ether	mg/kg		5	n. d.
六溴聯苯醚 / Hexabromodiphenyl ether	mg/kg		5	n. d.
七溴聯苯醚 / Heptabromodiphenyl ether	mg/kg		5	n. d.
八溴聯苯醚 / Octabromodiphenyl ether	mg/kg		5	n. d.
九溴聯苯醚 / Nonabromodiphenyl ether	mg/kg	5	n. d.	
十溴聯苯醚 / Decabromodiphenyl ether	mg/kg	5	n. d.	

This document is issued by the Company subject to its General Conditions of Service printed overleaf, available on request or accessible at <http://www.sgs.com.tw/terms-and-conditions.aspx> and, for electronic format documents, subject to Terms and Conditions for Electronic Documents at <http://www.sgs.com.tw/terms-and-conditions.aspx>. Attention is drawn to the limitation of liability, indemnification and jurisdiction issues defined therein. Any holder of this document is advised that information contained hereon reflects the Company's findings at the time of its intervention only and within the limits of client's instruction, if any. The Company's sole responsibility is to its Client and this document does not exonerate parties to a transaction from exercising all their rights and obligations under the transaction documents. This document cannot be reproduced, except in full, without prior written approval of the Company. Any unauthorized alteration, forgery or falsification of the content or appearance of this document is unlawful and offenders may be prosecuted to the fullest extent of the law. Unless otherwise stated the results shown in this test report refer only to the sample(s) tested.



測試報告 Test Report

號碼(No.) : CE/2015/C2559 日期(Date) : 2015/12/21

頁數(Page): 7 of 16

西北壹慶科技股份有限公司 / TAI-TECH ADVANCED ELECTRONICS CO., LTD.

(臺慶精密電子(昆山)有限公司 / TAI-TECH ADVANCED ELECTRONICS (KUN-SHAN) CO. LTD.)

(耀鑽科技股份有限公司 / YOSONIC TECHNOLOGY CO., LTD.)

(慶邦電子元器件(泗洪)有限公司 / TAIPAQ ELECTRONICS (SI-HONG) CO., LTD.)

桃園市楊梅區幼獅工業區幼四路1號 (NO. 1, YOU 4TH ROAD, YOUTH INDUSTRIAL DISTRICT, YANG-MEI, TAO-YUAN CITY, TAIWAN, R. O. C.)

(江蘇省昆山市蓬朗昆嘉高科技工業區郭澤路 / GUO-ZE ROAD, KUNJIA HI-TECH INDUSTRIAL PARK, KUN-SHAN, JIANG-SU, CHINA)

(桃園市中壢區中壢工業區長春六路15號 / NO. 15, CHANGCHUN 6TH RD., JHONGLI DISTRICT, TAOYUAN CITY 320, TAIWAN)

(江蘇省宿遷市泗洪縣經濟開發區金沙南路-高新技術產業園 / HIGH-TECH INDUSTRIAL DISTRICT, JINSHAJIANG ROAD, SIHONG COUNTY ECONOMIC, SUQIAN CITY, JIANGSU)

備註(Note) :

1. mg/kg = ppm ; 0.1wt% = 1000ppm
2. n. d. = Not Detected (未檢出)
3. MDL = Method Detection Limit (方法偵測極限值)
4. "-" = Not Regulated (無規格值)
5. **= Qualitative analysis (No Unit) 定性分析(無單位)
6. Negative = Undetectable 陰性(未偵測到); Positive = Detectable 陽性(已偵測到)
7. 樣品的測試是基於申請人要求混合測試, 報告中的混合測試結果不代表其中個別單一材質的含量。(The samples was/were analyzed on behalf of the applicant as mixing sample in one testing. The above results was/were only given as the informality value.)

PFOS參考資訊(Reference Information) : 持久性有機污染物 POPs - (EU) 757/2010

PFOS濃度在物質或製備中不得超過0.001%(10ppm), 在半成品、成品或零部件中不得超過0.1%(1000ppm), 在紡織品或塗層材料中不得超過 $1\mu\text{g}/\text{m}^2$ 。

(Outlawing PFOS as substances or preparations in concentrations above 0.001% (10ppm), in semi-finished products or articles or parts at a level above 0.1%(1000ppm), in textiles or other coated materials above $1\mu\text{g}/\text{m}^2$.)

This document is issued by the Company subject to its General Conditions of Service printed overleaf, available on request or accessible at <http://www.sgs.com/en/terms-and-conditions.aspx> and, for electronic format documents, subject to Terms and Conditions for Electronic Documents at <http://www.sgs.com/en/terms-and-conditions/terms-document.aspx>. Attention is drawn to the limitation of liability, indemnification and jurisdiction issues defined therein. Any holder of this document is advised that information contained herein reflects the Company's findings at the time of its intervention only and within the limits of client's instruction, if any. The Company's sole responsibility is to its Client and this document does not exonerate parties to a transaction from exercising all their rights and obligations under the transaction documents. This document cannot be reproduced, except in full, without prior written approval of the Company. Any unauthorized alteration, forgery or falsification of the content or appearance of this document is unlawful and offenders may be prosecuted to the fullest extent of the law. Unless otherwise stated the results shown in this test report refer only to the sample(s) tested.



測試報告 Test Report

號碼(No.) : CE/2015/C2559

日期(Date) : 2015/12/21

頁數(Page): 8 of 16

西北臺慶科技股份有限公司 / TAI-TECH ADVANCED ELECTRONICS CO., LTD.

(臺慶精密電子(昆山)有限公司 / TAI-TECH ADVANCED ELECTRONICS (KUN-SHAN) CO. LTD.)

(耀鑽科技股份有限公司 / YOSONIC TECHNOLOGY CO., LTD.)

(慶邦電子元器件(泗洪)有限公司 / TAIPAQ ELECTRONICS (SI-HONG) CO., LTD.)

桃園市楊梅區幼獅工業區幼四路1號 (NO. 1, YOU 4TH ROAD, YOUTH INDUSTRIAL DISTRICT, YANG-MEI, TAO-YUAN CITY, TAIWAN, R. O. C.)

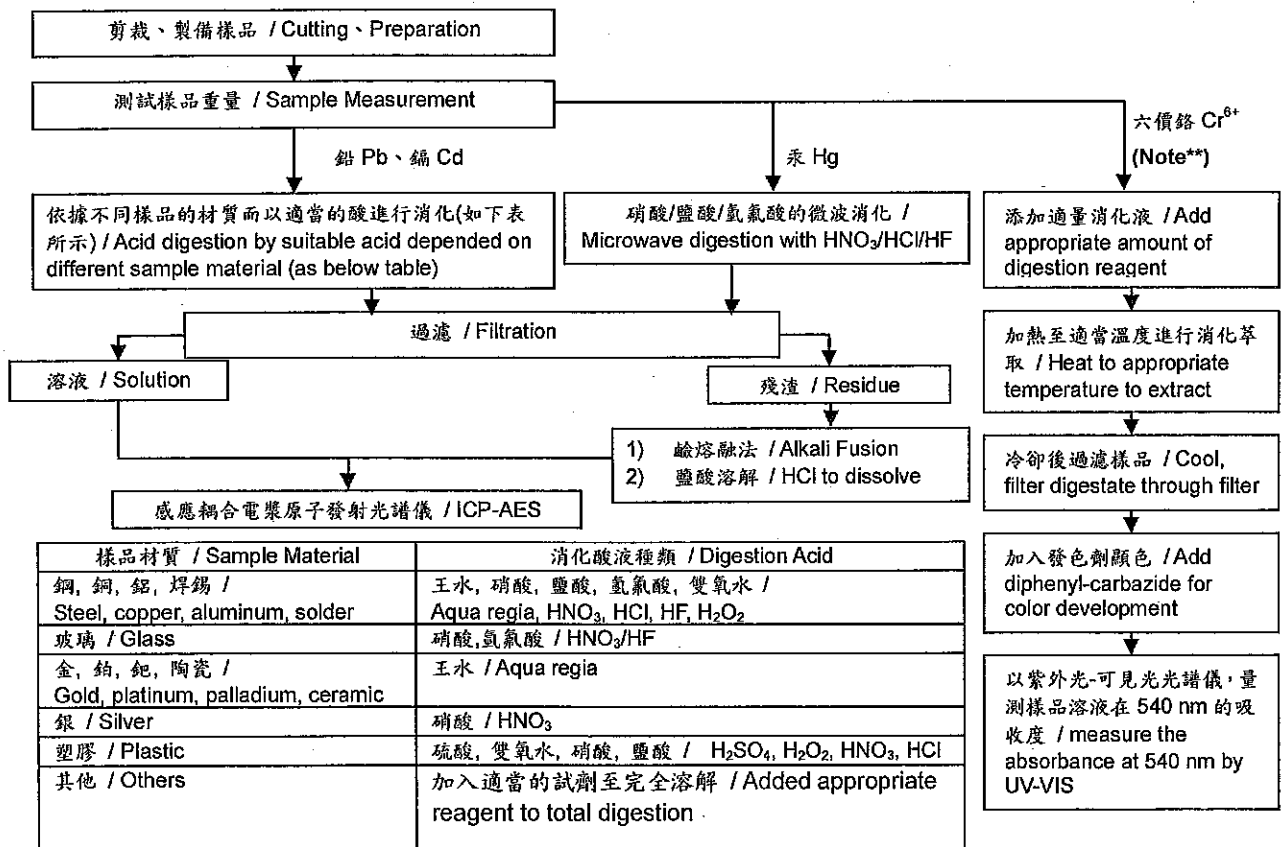
(江蘇省昆山市蓬朗鎮嘉高科技工業區郭澤路 / GUO-ZE ROAD, KUNJIA HI-TECH INDUSTRIAL PARK, KUN-SHAN, JIANG-SU, CHINA)

(桃園市中壢區中壢工業區長春六路15號 / NO. 15, CHANGCHUN 6TH RD., JHONGLI DISTRICT, TAOYUAN CITY 320, TAIWAN)

(江蘇省宿遷市泗洪縣經濟開發區金沙南路-高新技術產業園 / HIGH-TECH INDUSTRIAL DISTRICT, JINSHAJIANG ROAD, SIHONG COUNTY ECONOMIC, SUQIAN CITY, JIANGSU)

重金屬流程圖 / Analytical flow chart of Heavy Metal (IEC 62321)

- 1) 根據以下的流程圖之條件，樣品已完全溶解。(六價鉻測試方法除外) / These samples were dissolved totally by pre-conditioning method according to below flow chart. (Cr⁶⁺ test method excluded)
- 2) 測試人員：楊登偉 / Name of the person who made measurement: Climbgreat Yang
- 3) 測試負責人：張啟興 / Name of the person in charge of measurement: Troy Chang



Note**: (1) 針對非金屬材料加入鹼性消化液，加熱至 90~95°C 萃取。 / For non-metallic material, add alkaline digestion reagent and heat to 90~95°C.

(2) 針對金屬材料加入純水，加熱至沸騰萃取。 / For metallic material, add pure water and heat to boiling.

This document is issued by the Company subject to its General Conditions of Service printed overleaf, available on request or accessible at <http://www.sgs.com.tw/terms-and-conditions.aspx> and, for electronic format documents, subject to Terms and Conditions for Electronic Documents at <http://www.sgs.com.tw/terms-and-conditions/interactivedocuments.aspx>. Attention is drawn to the limitation of liability, indemnification and jurisdiction issues defined therein. Any holder of this document is advised that information contained hereon reflects the Company's findings at the time of its intervention only and within the limits of client's instruction, if any. The Company's sole responsibility is to its Client and this document does not exonerate parties to a transaction from exercising all their rights and obligations under the transaction documents. This document cannot be reproduced, except in full, without prior written approval of the Company. Any unauthorized alteration, forgery or falsification of the content or appearance of this document is unlawful and offenders may be prosecuted to the fullest extent of the law. Unless otherwise stated the results shown in this test report refer only to the sample(s) tested.



測試報告 Test Report

號碼(No.) : CE/2015/C2559

日期(Date) : 2015/12/21

頁數(Page): 9 of 16

西北臺慶科技股份有限公司 / TAI-TECH ADVANCED ELECTRONICS CO., LTD.

(臺慶精密電子(昆山)有限公司 / TAI-TECH ADVANCED ELECTRONICS (KUN-SHAN) CO. LTD.)

(耀鑽科技股份有限公司 / YOSONIC TECHNOLOGY CO., LTD.)

(慶邦電子元件(泗洪)有限公司 / TAIPAQ ELECTRONICS (SI-HONG) CO., LTD.)

桃園市楊梅區幼獅工業區幼四路1號 (NO. 1, YOU 4TH ROAD, YOUTH INDUSTRIAL DISTRICT, YANG-MEI, TAO-YUAN CITY, TAIWAN, R. O. C.)

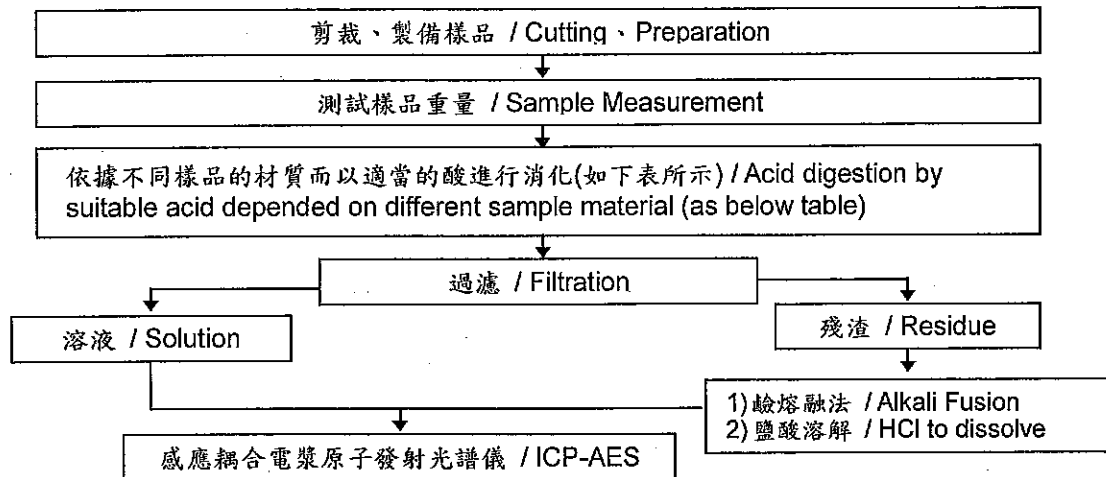
(江蘇省昆山市蓬朗昆嘉高科技工業區郭澤路 / GUO-ZE ROAD, KUNJIA HI-TECH INDUSTRIAL PARK, KUN-SHAN, JIANG-SU, CHINA)

(桃園市中壢區中壢工業區長春六路15號 / NO. 15, CHANGCHUN 6TH RD., JHONGLI DISTRICT, TAOYUAN CITY 320, TAIWAN)

(江蘇省宿遷市泗洪縣經濟開發區金沙南路-高新技術產業園 / HIGH-TECH INDUSTRIAL DISTRICT, JINSHAJIANG ROAD, SIHONG COUNTY ECONOMIC, SUQIAN CITY, JIANGSU)

- 根據以下的流程圖之條件，樣品已完全溶解。 / These samples were dissolved totally by pre-conditioning method according to below flow chart.
- 測試人員：楊登偉 / Name of the person who made measurement: Climbgreat Yang
- 測試負責人：張啟興 / Name of the person in charge of measurement: Troy Chang

元素以 ICP-AES 分析的消化流程圖 (Flow Chart of digestion for the elements analysis performed by ICP-AES)



鋼,銅,鋁,焊錫 / Steel, copper, aluminum, solder	王水,硝酸,鹽酸,氫氟酸,雙氧水 / Aqua regia, HNO ₃ , HCl, HF, H ₂ O ₂
玻璃 / Glass	硝酸,氫氟酸 / HNO ₃ /HF
金,鉑,鈀,陶瓷 / Gold, platinum, palladium, ceramic	王水 / Aqua regia
銀 / Silver	硝酸 / HNO ₃
塑膠 / Plastic	硫酸,雙氧水,硝酸,鹽酸 / H ₂ SO ₄ , H ₂ O ₂ , HNO ₃ , HCl
其他 / Others	加入適當的試劑至完全溶解 / Added appropriate reagent to total digestion

This document is issued by the Company subject to its General Conditions of Service printed overleaf, available on request or accessible at <http://www.sgs.com.tw/Terms-and-Conditions.aspx> and, for electronic format documents, subject to Terms and Conditions for Electronic Documents at <http://www.sgs.com.tw/terms-and-conditions-for-electronic-documents.aspx>. Attention is drawn to the limitation of liability, indemnification and jurisdiction issues defined therein. Any holder of this document is advised that information contained hereon reflects the Company's findings at the time of its intervention only and within the limits of client's instruction, if any. The Company's sole responsibility is to its Client and this document does not exonerate parties to a transaction from exercising all their rights and obligations under the transaction documents. This document cannot be reproduced, except in full, without prior written approval of the Company. Any unauthorized alteration, forgery or falsification of the content or appearance of this document is unlawful and offenders may be prosecuted to the fullest extent of the law. Unless otherwise stated the results shown in this test report refer only to the sample(s) tested.



測試報告 Test Report

號碼(No.) : CE/2015/C2559 日期(Date) : 2015/12/21

頁數(Page): 10 of 16

西北臺慶科技股份有限公司 / TAI-TECH ADVANCED ELECTRONICS CO., LTD.

(臺慶精密電子(昆山)有限公司 / TAI-TECH ADVANCED ELECTRONICS (KUN-SHAN) CO. LTD.)

(耀鑽科技股份有限公司 / YOSONIC TECHNOLOGY CO., LTD.)

(慶邦電子元件(泗洪)有限公司 / TAIPAQ ELECTRONICS (SI-HONG) CO., LTD.)

桃園市楊梅區幼獅工業區幼四路1號 (NO. 1, YOU 4TH ROAD, YOUTH INDUSTRIAL DISTRICT, YANG-MEI, TAO-YUAN CITY, TAIWAN, R. O. C.)

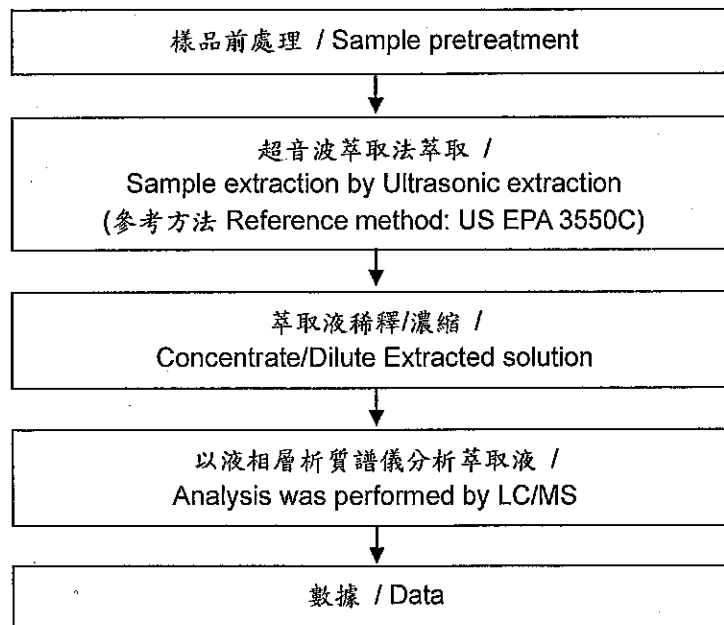
(江蘇省昆山市蓬朗鎮嘉高科技工業區郭澤路 / GUO-ZE ROAD, KUNJIA HI-TECH INDUSTRIAL PARK, KUN-SHAN, JIANG-SU, CHINA)

(桃園市中壢區中壢工業區長春六路15號 / NO. 15, CHANGCHUN 6TH RD., JIONGLI DISTRICT, TAOYUAN CITY 320, TAIWAN)

(江蘇省宿遷市泗洪縣經濟開發區金沙南路-高新技術產業園 / HIGH-TECH INDUSTRIAL DISTRICT, JINSHAJIANG ROAD, SIHONG COUNTY ECONOMIC, SUQIAN CITY, JIANGSU)

全氟辛酸/全氟辛烷磺酸分析流程圖 / PFOA/PFOS analytical flow chart

- 測試人員：翁賜彬 / Name of the person who made measurement: Roman Wong
- 測試負責人：張啟興 / Name of the person in charge of measurement: Troy Chang



This document is issued by the Company subject to its General Conditions of Service printed overleaf, available on request or accessible at <http://www.sgs.com.tw/Terms-and-Conditions.aspx> and, for electronic format documents, subject to Terms and Conditions for Electronic Documents at <http://www.sgs.com.tw/Terms-and-Conditions/ETD/ETD.aspx>. Attention is drawn to the limitation of liability, indemnification and jurisdiction issues defined therein. Any holder of this document is advised that information contained hereon reflects the Company's findings at the time of its intervention only and within the limits of client's instruction, if any. The Company's sole responsibility is to its Client and this document does not exonerate parties to a transaction from exercising all their rights and obligations under the transaction documents. This document cannot be reproduced, except in full, without prior written approval of the Company. Any unauthorized alteration, forgery or falsification of the content or appearance of this document is unlawful and offenders may be prosecuted to the fullest extent of the law. Unless otherwise stated the results shown in this test report refer only to the sample(s) tested.



測試報告 Test Report

號碼(No.) : CE/2015/C2559

日期(Date) : 2015/12/21

頁數(Page): 11 of 16

西北臺慶科技股份有限公司 / TAI-TECH ADVANCED ELECTRONICS CO., LTD.

(臺慶精密電子(昆山)有限公司 / TAI-TECH ADVANCED ELECTRONICS (KUN-SHAN) CO. LTD.)

(耀鑽科技股份有限公司 / YOSONIC TECHNOLOGY CO., LTD.)

(慶邦電子元器件(泗洪)有限公司 / TAIPAQ ELECTRONICS (SI-HONG) CO., LTD.)

桃園市楊梅區幼獅工業區幼四路1號 (NO. 1, YOU 4TH ROAD, YOUTH INDUSTRIAL DISTRICT, YANG-MEI, TAO-YUAN CITY, TAIWAN, R. O. C.)

(江蘇省昆山市蓬朗區嘉高科技工業區郭澤路 / GUO-ZE ROAD, KUNJIA HI-TECH INDUSTRIAL PARK, KUN-SHAN, JIANG-SU, CHINA)

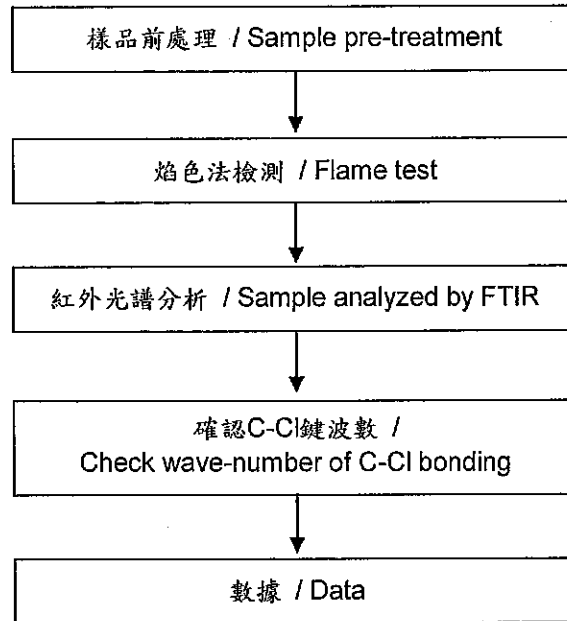
(桃園市中壢區中壢工業區長春六路15號 / NO. 15, CHANGCHUN 6TH RD., JHONGLI DISTRICT, TAOYUAN CITY 320, TAIWAN)

(江蘇省宿遷市泗洪縣經濟開發區金沙南路-高新技術產業園 / HIGH-TECH INDUSTRIAL DISTRICT, JINSHAJIANG ROAD, SIHONG COUNTY ECONOMIC, SUQIAN CITY, JIANGSU)

聚氯乙稀物質判定分析流程圖 /

Analysis flow chart for determination of PVC in material

- 測試人員：林建宇 / Name of the person who made measurement: Roy Lin
- 測試負責人：張啟興 / Name of the person in charge of measurement: Troy Chang



This document is issued by the Company subject to its General Conditions of Service printed overleaf, available on request or accessible at <http://www.sgs.com.tw/terms-and-conditions.aspx> and, for electronic format documents, subject to Terms and Conditions for Electronic Documents at <http://www.sgs.com.tw/terms-and-conditions-for-electronic-documents.aspx>. Attention is drawn to the limitation of liability, indemnification and jurisdiction issues defined therein. Any holder of this document is advised that information contained hereon reflects the Company's findings at the time of its intervention only and within the limits of client's instruction, if any. The Company's sole responsibility is to its Client and this document does not exonerate parties to a transaction from exercising all their rights and obligations under the transaction documents. This document cannot be reproduced, except in full, without prior written approval of the Company. Any unauthorized alteration, forgery or falsification of the content or appearance of this document is unlawful and offenders may be prosecuted to the fullest extent of the law. Unless otherwise stated the results shown in this test report refer only to the sample(s) tested.



測試報告 Test Report

號碼(No.) : CE/2015/C2559 日期(Date) : 2015/12/21

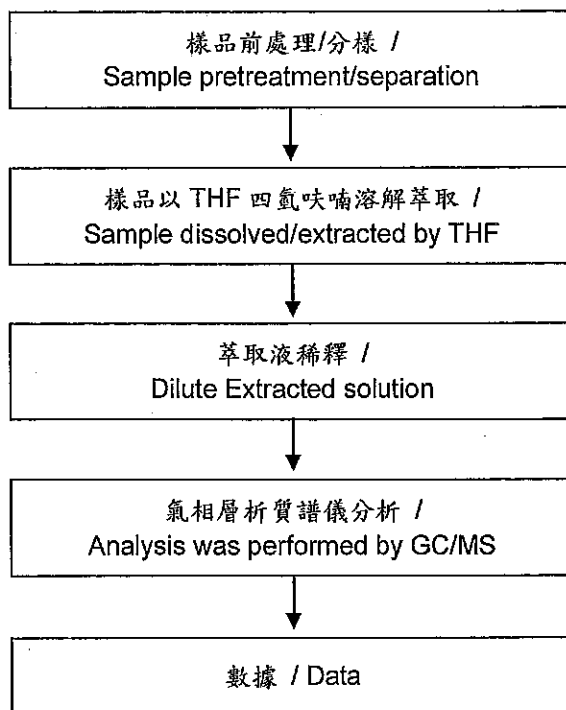
頁數(Page): 12 of 16

西北臺慶科技股份有限公司 / TAI-TECH ADVANCED ELECTRONICS CO., LTD.
 (臺慶精密電子(昆山)有限公司 / TAI-TECH ADVANCED ELECTRONICS (KUN-SHAN) CO. LTD.)
 (耀鑽科技股份有限公司 / YOSONIC TECHNOLOGY CO., LTD.)
 (慶邦電子元器件(泗洪)有限公司 / TAIPAQ ELECTRONICS (SI-HONG) CO., LTD.)
 桃園市楊梅區幼獅工業區幼四路1號 (NO. 1, YOU 4TH ROAD, YOUTH INDUSTRIAL DISTRICT, YANG-MEI, TAO-YUAN CITY, TAIWAN, R. O. C.)
 (江蘇省昆山市蓬朗昆嘉高科技工業區郭澤路 / GUO-ZE ROAD, KUNJIA HI-TECH INDUSTRIAL PARK, KUN-SHAN, JIANG-SU, CHINA)
 (桃園市中壢區中壢工業區長春六路15號 / NO. 15, CHANGCHUN 6TH RD., JHONGLI DISTRICT, TAOYUAN CITY 320, TAIWAN)
 (江蘇省宿遷市泗洪縣經濟開發區金沙南路-高新技術產業園 / HIGH-TECH INDUSTRIAL DISTRICT, JINSHAJIANG ROAD, SIIHONG COUNTY ECONOMIC, SUQIAN CITY, JIANGSU)

可塑劑分析流程圖 / Analytical flow chart of phthalate content

- 測試人員：徐毓明 / Name of the person who made measurement: Andy Shu
- 測試負責人：張啟興 / Name of the person in charge of measurement: Troy Chang

【測試方法/Test method: IEC 62321-8】



This document is issued by the Company subject to its General Conditions of Service printed overleaf, available on request or accessible at <http://www.sgs.com/en/Terms-and-Conditions.aspx> and, for electronic format documents, subject to Terms and Conditions for Electronic Documents at <http://www.sgs.com/en/Terms-and-Conditions/ETD.aspx>. Attention is drawn to the limitation of liability, indemnification and jurisdiction issues defined therein. Any holder of this document is advised that information contained hereon reflects the Company's findings at the time of its intervention only and within the limits of client's instruction, if any. The Company's sole responsibility is to its Client and this document does not exonerate parties to a transaction from exercising all their rights and obligations under the transaction documents. This document cannot be reproduced, except in full, without prior written approval of the Company. Any unauthorized alteration, forgery or falsification of the content or appearance of this document is unlawful and offenders may be prosecuted to the fullest extent of the law. Unless otherwise stated the results shown in this test report refer only to the sample(s) tested.



測試報告 Test Report

號碼(No.) : CE/2015/C2559 日期(Date) : 2015/12/21

頁數(Page): 13 of 16

西北臺慶科技股份有限公司 / TAI-TECH ADVANCED ELECTRONICS CO., LTD.

(臺慶精密電子(昆山)有限公司 / TAI-TECH ADVANCED ELECTRONICS (KUN-SHAN) CO. LTD.)

(耀鑽科技股份有限公司 / YOSONIC TECHNOLOGY CO., LTD.)

(慶邦電子元器件(泗洪)有限公司 / TAIPAQ ELECTRONICS (SI-HONG) CO., LTD.)

桃園市楊梅區幼獅工業區幼四路1號 (NO. 1, YOU 4TH ROAD, YOUTH INDUSTRIAL DISTRICT, YANG-MEI, TAO-YUAN CITY, TAIWAN, R. O. C.)

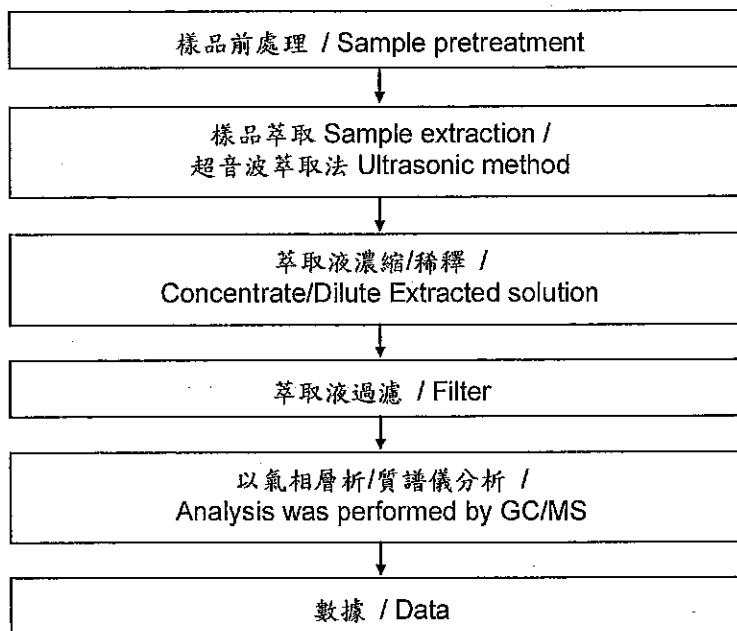
(江蘇省昆山市蓬朗昆嘉高科技工業區郭澤路 / GUO-ZE ROAD, KUNJIA HI-TECH INDUSTRIAL PARK, KUN-SHAN, JIANG-SU, CHINA)

(桃園市中壢區中壢工業區長春六路15號 / NO. 15, CHANGCHUN 6TH RD., JHONGLI DISTRICT, TAOYUAN CITY 320, TAIWAN)

(江蘇省宿遷市泗洪縣經濟開發區金沙南路-高新技術產業園 / HIGH-TECH INDUSTRIAL DISTRICT, JINSHAJIANG ROAD, SIHONG COUNTY ECONOMIC, SUQIAN CITY, JIANGSU)

六溴環十二烷分析流程圖 / HBCDD analytical flow chart

- 測試人員：翁賜彬 / Name of the person who made measurement: Roman Wong
- 測試負責人：張啟興 / Name of the person in charge of measurement: Troy Chang



This document is issued by the Company subject to its General Conditions of Service printed overleaf, available on request or accessible at <http://www.sgs.com.tw/terms-and-conditions.aspx> and, for electronic format documents, subject to Terms and Conditions for Electronic Documents at <http://www.sgs.com.tw/terms-and-conditions-for-electronic-documents.aspx>. Attention is drawn to the limitation of liability, indemnification and jurisdiction issues defined therein. Any holder of this document is advised that information contained hereon reflects the Company's findings at the time of its intervention only and within the limits of client's instruction, if any. The Company's sole responsibility is to its Client and this document does not exonerate parties to a transaction from exercising all their rights and obligations under the transaction documents. This document cannot be reproduced, except in full, without prior written approval of the Company. Any unauthorized alteration, forgery or falsification of the content or appearance of this document is unlawful and offenders may be prosecuted to the fullest extent of the law. Unless otherwise stated the results shown in this test report refer only to the sample(s) tested.



測試報告 Test Report

號碼(No.) : CE/2015/C2559 日期(Date) : 2015/12/21

頁數(Page): 14 of 16

西北臺慶科技股份有限公司 / TAI-TECH ADVANCED ELECTRONICS CO., LTD.

(臺慶精密電子(昆山)有限公司 / TAI-TECH ADVANCED ELECTRONICS (KUN-SHAN) CO. LTD.)

(耀鑽科技股份有限公司 / YOSONIC TECHNOLOGY CO., LTD.)

(慶邦電子元器件(泗洪)有限公司 / TAIPAQ ELECTRONICS (SI-HONG) CO., LTD.)

桃園市楊梅區幼獅工業區幼四路1號 (NO. 1, YOU 4TH ROAD, YOUTH INDUSTRIAL DISTRICT, YANG-MEI, TAO-YUAN CITY, TAIWAN, R. O. C.)

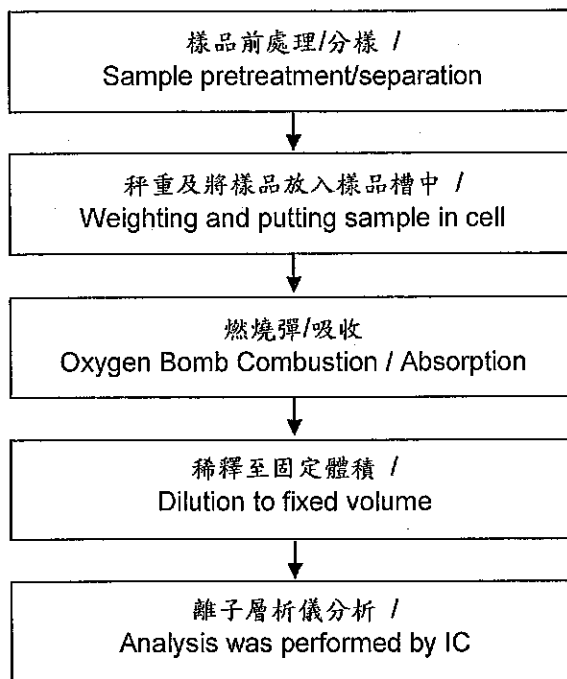
(江蘇省昆山市蓬朗昆嘉高科技工業區郭澤路 / GUO-ZE ROAD, KUNJIA HI-TECH INDUSTRIAL PARK, KUN-SHAN, JIANG-SU, CHINA)

(桃園市中壢區中壢工業區長春六路15號 / NO. 15, CHANGCHUN 6TH RD., JHONGLI DISTRICT, TAOYUAN CITY 320, TAIWAN)

(江蘇省宿遷市泗洪縣經濟開發區金沙南路-高新技術產業園 / HIGH-TECH INDUSTRIAL DISTRICT, JINSHAJIANG ROAD, SIHONG COUNTY ECONOMIC, SUQIAN CITY, JIANGSU)

鹵素分析流程圖 / Analytical flow chart of halogen content

- 測試人員：陳恩臻 / Name of the person who made measurement: Rita Chen
- 測試負責人：張啟興 / Name of the person in charge of measurement: Troy Chang



This document is issued by the Company subject to its General Conditions of Service printed overleaf, available on request or accessible at <http://www.sgs.com.tw/terms-and-conditions.aspx> and, for electronic format documents, subject to Terms and Conditions for Electronic Documents at <http://www.sgs.com.tw/terms-and-conditions/terms-and-conditions.aspx>. Attention is drawn to the limitation of liability, indemnification and jurisdiction issues defined therein. Any holder of this document is advised that information contained hereon reflects the Company's findings at the time of its intervention only and within the limits of client's instruction, if any. The Company's sole responsibility is to its Client and this document does not exonerate parties to a transaction from exercising all their rights and obligations under the transaction documents. This document cannot be reproduced, except in full, without prior written approval of the Company. Any unauthorized alteration, forgery or falsification of the content or appearance of this document is unlawful and offenders may be prosecuted to the fullest extent of the law. Unless otherwise stated the results shown in this test report refer only to the sample(s) tested.



測試報告 Test Report

號碼(No.) : CE/2015/C2559

日期(Date) : 2015/12/21

頁數(Page): 15 of 16

西北臺慶科技股份有限公司 / TAI-TECH ADVANCED ELECTRONICS CO., LTD.

(臺慶精密電子(昆山)有限公司 / TAI-TECH ADVANCED ELECTRONICS (KUN-SHAN) CO. LTD.)

(耀鑽科技股份有限公司 / YOSONIC TECHNOLOGY CO., LTD.)

(慶邦電子元器件(泗洪)有限公司 / TAIPAQ ELECTRONICS (SI-HONG) CO., LTD.)

桃園市楊梅區幼獅工業區幼四路1號 (NO. 1, YOU 4TH ROAD, YOUTH INDUSTRIAL DISTRICT, YANG-MEI, TAO-YUAN CITY, TAIWAN, R. O. C.)

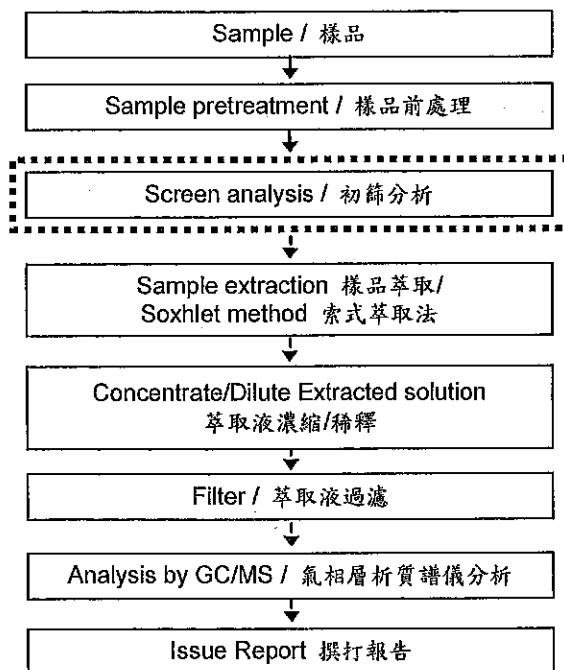
(江蘇省昆山市蓬朗昆嘉高科技工業區郭澤路 / GUO-ZE ROAD, KUNJIA HI-TECH INDUSTRIAL PARK, KUN-SHAN, JIANG-SU, CHINA)

(桃園市中壢區中壢工業區長春六路15號 / NO. 15, CHANGCHUN 6TH RD., JHONGLI DISTRICT, TAOYUAN CITY 320, TAIWAN)

(江蘇省宿遷市泗洪縣經濟開發區金沙南路-高新技術產業園 / HIGH-TECH INDUSTRIAL DISTRICT, JINSHAJIANG ROAD, SIHONG COUNTY ECONOMIC, SUQIAN CITY, JIANGSU)

多溴聯苯/多溴聯苯醚分析流程圖 / PBB/PBDE analytical FLOW CHART

- 測試人員: 翁賜彬 / Name of the person who made measurement: Roman Wong
 - 測試負責人: 張啟興 / Name of the person in charge of measurement: Troy Chang
- 初次測試程序 / First testing process →
- 選擇性篩檢程序 / Optional screen process ·····
- 確認程序 / Confirmation process - - -



This document is issued by the Company subject to its General Conditions of Service printed overleaf, available on request or accessible at <http://www.sgs.com.tw/terms-and-conditions.aspx> and, for electronic format documents, subject to Terms and Conditions for Electronic Documents at <http://www.sgs.com.tw/terms-and-conditions/innova/innova-terms.aspx>. Attention is drawn to the limitation of liability, indemnification and jurisdiction issues defined therein. Any holder of this document is advised that information contained hereon reflects the Company's findings at the time of its intervention only and within the limits of client's instruction, if any. The Company's sole responsibility is to its Client and this document does not exonerate parties to a transaction from exercising all their rights and obligations under the transaction documents. This document cannot be reproduced, except in full, without prior written approval of the Company. Any unauthorized alteration, forgery or falsification of the content or appearance of this document is unlawful and offenders may be prosecuted to the fullest extent of the law. Unless otherwise stated the results shown in this test report refer only to the sample(s) tested.

測試報告 Test Report

號碼(No.) : CE/2015/C2559 日期(Date) : 2015/12/21

頁數(Page): 16 of 16

西北臺慶科技股份有限公司 / TAI-TECH ADVANCED ELECTRONICS CO., LTD.

(臺慶精密電子(昆山)有限公司 / TAI-TECH ADVANCED ELECTRONICS (KUN-SHAN) CO. LTD.)

(耀鑽科技股份有限公司 / YOSONIC TECHNOLOGY CO., LTD.)

(慶邦電子元器件(泗洪)有限公司 / TAIPAQ ELECTRONICS (SI-HONG) CO., LTD.)

桃園市楊梅區幼獅工業區幼四路1號 (NO. 1, YOU 4TH ROAD, YOUTH INDUSTRIAL DISTRICT, YANG-MEI, TAO-YUAN CITY, TAIWAN, R. O. C.)

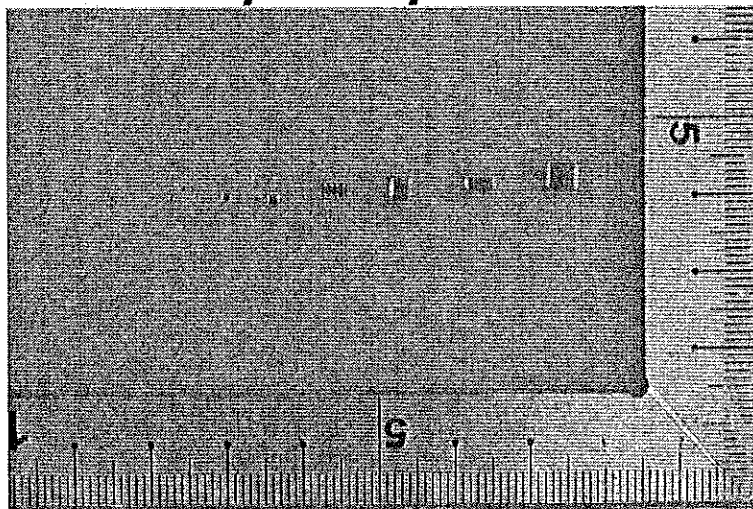
(江蘇省昆山市蓬朗昆嘉高科技工業區郭澤路 / GUO-ZE ROAD, KUNJIA HI-TECH INDUSTRIAL PARK, KUN-SHAN, JIANG-SU, CHINA)

(桃園市中壢區中壢工業區長春六路15號 / NO. 15, CHANGCHUN 6TH RD., JHONGLI DISTRICT, TAOYUAN CITY 320, TAIWAN)

(江蘇省宿遷市泗洪縣經濟開發區金沙南路-高新技術產業園 / HIGH-TECH INDUSTRIAL DISTRICT, JINSHAJIANG ROAD, SIHONG COUNTY ECONOMIC, SUQIAN CITY, JIANGSU)

* 照片中如有箭頭標示，則表示為實際檢測之樣品/部位。 *
(The tested sample / part is marked by an arrow if it's shown on the photo.)

CE/2015/C2559



** 報告結尾 (End of Report) **